Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/828,692	NEGISHI ET AL.	
Examiner	Art Unit	
Michael Y. Won	2155	

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	202, 216, 219, 246	9/27/2007	MVV
710	1, 10	9/27/2007	MW
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INT	INTERFERENCE SEARCHED		
· Class	Subclass	Date	Examiner
709	219	10/2/2007	MW
	1		-

SEARCH N (INCLUDING SEARC)
· · ·	DATE	EXMR
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	9/27/2007	MW
NPL SEARCH: IEEE	9/27/2007	MW
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	10/2/2007	MW
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